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PAJ 00-66-76 04172537 JP **FAILURE ANALYSIS METHOD FOR INFORMATION PROCESSOR**

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PATENT APPLICATION NUMBER- 02299716
DATE FILED- 1990-11-07
PUBLICATION NUMBER- 04172537 JP
DOCUMENT TYPE- A
PUBLICATION DATE- 1992-06-19
INTERNATIONAL PATENT CLASS- G06F01122
APPLICANT(S)- HITACHI LTD; HITACHI ELECTRON SERVICE CO LTD
PUBLICATION COUNTRY- Japan NDN- 190-0100-1972-9

PURPOSE: To enhance indicated resolution and precision of a defective part when the defect occurs by referring to a failure dictionary for parts including components of the processor, and by indicating a processor component part group included in a limited cover area as defective parts. CONSTITUTION: A failure dictionary 20 is prepared on the basis of a result of extracting in advance a cover area for total failure detecting circuit, and consists of a failure detecting circuit, processor components, and correspondence information for selector signals, cover for failure defecting circuit, information of connecting between logical elements included in the area, and so on. Failure analysis section 100 recognizes a leading light failure detecting circuit (FD) from a detected state of failure information 10, obtains bus selecting information from information 10 and the corresponding information of selector signals stored in dictionary 20, analyses the bus selecting information, and specifies a data transfer bus in the case of the occurrence of a failure. Failure analysis section 200 extracts a cover area from the content of the register of information 10 and inter-register connecting information. Failure analysis section 300 extracts a cover area for the case where a plurality of FDs exist. With this, a cover area is limited, thereby enhancing the indicated resolution and its accuracy.

NO-DESCRIPTORS

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